PCN Number: 2		202	20211004002.1			PC	N Date:	October 06, 2021		
Title: DP83826 Design C		gn C	Change and Datasheet Update							
Customer Contact:				PCN Manager Dept:			Dept:	Quality Se		ervices
Proposed 1 st Ship Date:							Estimated Sample Availability:		Date provided at sample request.	
Change Type:										
Assembly Site				Assembly Process				Assembly Materials		
Design			\boxtimes	Electrical Specification				Mechanica	Specification	
Test Site				Packing/Shipping/Labeling				Test Proce	SS	
Wafer Bump Site				Wafer Bump Material				Wafer Bum	np Process	
Wafer Fab Site				Wafer Fab Materials				Wafer Fab	Process	
					Part number change					
	PCN Details									

Description of Change:

This notification is to inform of a design change to the DP83826 devices. Affected devices are listed in the Product Affected section of this document.

The minor metal design change was performed for device improvements highlighted in the Datasheet change.

The datasheet revision will be changing:

	Current	New
Product Family	Datasheet Revision	Datasheet Revision
DP83826	SNLS647D	SNLS647E

The product datasheet(s) is being updated as summarized below:

TEXAS INSTRUMENTS	DP83826E, DP83826 SNLS647E – DECEMBER 2019 – REVISED SEPTEMBER 2021
hanges from Revision D (October 2020) to Revisi	on E (September 2021) Page
	le detection and FLD detection mechanisms in hardware
bootstrap differences table	4
Added TX ER to pin 28	5
	and pin 31 to PU8
Added fast link drop modes table, updated descript	ion for fast link drop functionality in Included specification
	sic mode, added strap8 description45
	hanced), active low by default (basic)46
	d strap1 interaction to MII MAC mode strap table, added
	hanged to half duplex50

This product change notification is considered the final datasheet notification. The product datasheet will be available after expiration of this PCN. Although the datasheet will not be published on the TI website for review, these documents are available. If customers require a preview datasheet prior to PCN expiration or have additional questions regarding the datasheet change, please contact geet.modi@ti.com.

Reason for Change:

Improved performance for customer use cases									
Anticipated impact or	Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):								
None									
Changes to product in	Changes to product identification resulting from this PCN:								
Die Rev designator will	change as shown in the	table and sample label	below:						
Current New Die Rev [2P] Die Rev [2P] A B Sample product shipping label (not actual product label)									
MADE IN: Malaysia 20: MSL '2 /260C/1 YEAR S MSL '2 /260C/1 YEAR S MSL 1 /235C/UNLIM 0 OPT: ITEM: LBL: 5A (L)TO:	G4 G4 EAL DT 3/29/04 39	(1P) SN74LSO (Q) 2000 (31T) LOT: 39 (4W) TKY (1T) (2P) REV: (20L) CSO: SHE	7NSR (D) 0336 59047MLA 7523483512 (V) 0033317 (21L) CCO:USA (23L) ACO: MYS						
Product Affected: Des	sign Change and data	sheet updates							
DP83826ERHBR	DP83826ERHBT	DP83826IRHBR	DP83826IRHBT						

Qualification Report

Approved- 09-03-21

	Data Displayed as: Number of lots / Total sample size / Total failed							
Туре	Test Name / Condition	Duration	Qual Device: DP83826ERHBRT	Qual Device: DP83826ERHBR	QBS: Device Reference DP83825IRMQR DP83825IRMQT	Qua Device Reference DP83825IRMQR DP83825IRMQT	QBS: Process References DS90UH947TRGCR Q1	
HTOL	High Temp Operating Life, 125C	1000 Hours	-	1/77/0	1/77/0	1/77/0	3/231/0	
HTOL	High Temp Operating Life, 125C	500 Hours	-	1/77/0	-	1/77/0	-	
ELFR	Early Life Failure Rate, 125C	48 Hours	-		-	-	3/2400/0	
TC	**T/C - 65C/150C	500 Cycles	-	1/77/0	3/231/0	-	3/231/0	
UHAST	Biased HAST, 130C/85% RH	96 Hours	-		3/231/0	-	3/231/0	
HAST	Biased HAST, 130C/85% RH	96 Hours	-		3/231/0	-	3/231/0	
HTSL	High Temp. Storage Bake	170C (168, 420 Hours)	-		3/231/0	-		
ED	Electrical Characterization	Limit Verification	Pass	Pass	-	Pass	Pass	
CDM	ESD CDM	1500V	-	1/3/0	1/3/0	1/3/0	1/3/0	
HBM	ESD HBM	4000V	-	1/3/0	1/3/0	1/3/0	1/3/0	
HBM	ESD HBM, MDI	5000V	-	1/3/0				

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

	Pins(Pins 4,5,6,7)						
LU	Latch-up, 25C	(per JESD78)	-	1/6/0	1/6/0	1/6/0	1/6/0
LU	Latch-up, 85C	(per JESD78)	-	1/6/0	1/6/0	1/6/0	1/6/0
BPC	Bond Pad Cratering Check	Post 500 Temp Cyc	-		3/5/0	-	
BPC	Bond Pad Cratering Check	Post assembly	-		3/6/0	-	
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	-	Pass	Pass	-	
TC-BP	Post T/C bond- pull strength	Wires	-		3/30/0	-	
TC- SAM	Post Temp Cycle SAM	Pre and Post MSL	-		3/30/0	-	
WBP	Bond Pull	Wires	-		3/228/0	-	
BLR	BLR - Temp Cycle (QFN), - 40/125C	1000 Cycles	-		1/32/0	-	
SD	Solderability w. Bake precon	4 Hours/@155C, Pb Free	-		3/45/0	-	
SD	Solderability w. Bake precon	4 Hours/@155C, Pb	_		3/45/0	-	
TPI	Thermal Path Integrity	MSL Level 2, 260C		1/12/0			

- QBS: Qual By Similarity

- Qual Device DP83826ERHBR is qualified at LEVEL2-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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